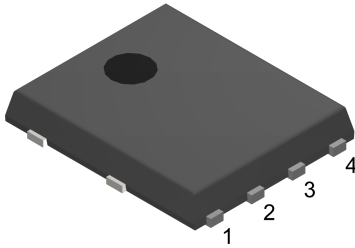
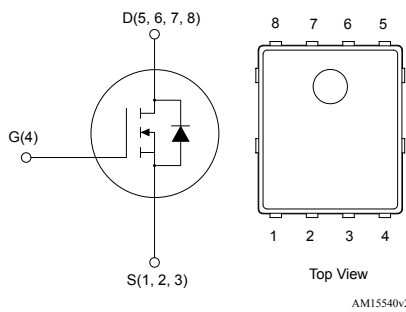


N-channel 300 V, 72 mΩ typ., 23 A MDmesh M8 Power MOSFET in a PowerFLAT 5x6 package



PowerFLAT™ 5x6



Features

| Order code | V _{DS} | R _{DS(on)} max. | I _D |
|------------|-----------------|--------------------------|----------------|
| STL26N30M8 | 300 V | 89 mΩ | 23 A |

- Very low R_{DS(on)} x area
- Extremely low gate charge and input capacitance
- Low gate resistance (R_G)
- 100% avalanche tested
- High dv/dt ruggedness

Applications

- Switching applications

Description

This high voltage N-channel Power MOSFET belongs to the MDmesh™ M8 series, based on the new ST trench super-junction technology. The resulting Power MOSFET exhibits very low R_{DS(on)} x area, low gate charge (Q_g) and low gate resistance (R_G), making it suitable for the most demanding high efficiency converters.

Product status

STL26N30M8

Device summary

| | |
|-------------------|----------------|
| Order code | STL26N30M8 |
| Marking | 26N30M8 |
| Package | PowerFLAT™ 5x6 |
| Packing | Tape and reel |

1 Electrical ratings

Table 1. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|-------------------|---|------------|------------------|
| V_{DS} | Drain-source voltage | 300 | V |
| V_{GS} | Gate-source voltage | ± 25 | V |
| $I_D^{(1)}$ | Drain current (continuous) at $T_c = 25\text{ }^\circ\text{C}$ | 23 | A |
| $I_D^{(1)}$ | Drain current (continuous) at $T_c = 100\text{ }^\circ\text{C}$ | 14.7 | A |
| $I_{DM}^{(1)(2)}$ | Drain current (pulsed) | 69 | A |
| $I_D^{(3)}$ | Drain current (continuous) at $T_{pcb} = 25\text{ }^\circ\text{C}$ | 4.4 | A |
| $I_D^{(3)}$ | Drain Current (continuous) at $T_{pcb} = 100\text{ }^\circ\text{C}$ | 2.8 | A |
| $I_{DM}^{(2)(3)}$ | Drain current (pulsed) | 17.6 | A |
| $P_{TOT}^{(1)}$ | Total dissipation at $T_c = 25\text{ }^\circ\text{C}$ | 114 | W |
| $P_{TOT}^{(3)}$ | Total dissipation at $T_{pcb} = 25\text{ }^\circ\text{C}$ | 4 | W |
| $dv/dt^{(4)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $dv/dt^{(5)}$ | MOSFET dv/dt ruggedness | 50 | V/ns |
| T_{stg} | Storage temperature range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating junction temperature range | | |

1. This value is rated according to R_{thj-c} .
2. Pulse width is limited by safe operating area.
3. This value is rated according to $R_{thj-pcb}$.
4. $I_{SD} \leq 23\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$; $V_{DS(peak)} < V_{(BR)DSS}$, $V_{DD} = 240\text{ V}$.
5. $V_{DS} \leq 240\text{ V}$.

Table 2. Thermal data

| Symbol | Parameter | Value | Unit |
|---------------------|----------------------------------|-------|---------------------------|
| R_{THJ-C} | Thermal resistance junction-case | 1.1 | $^\circ\text{C}/\text{W}$ |
| $R_{THJ-pcb}^{(1)}$ | Thermal resistance junction-pcb | 31.3 | $^\circ\text{C}/\text{W}$ |

1. When mounted on FR-4 board of 1 inch², 2 oz Cu, $t < 10\text{ s}$.

Table 3. Avalanche data

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax}) | 5 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$, $I_D = I_{AR}$; $V_{DD} = 50\text{ V}$) | 580 | mJ |

2 Electrical characteristics

($T_C = 25\text{ °C}$)

Table 4. On/off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|-----------------------------------|--|------|------|-----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$ | 300 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0\text{ V}$, $V_{DS} = 300\text{ V}$ | | | 1 | μA |
| I_{GSS} | Gate-source leakage current | $V_{DS} = 0\text{ V}$, $V_{GS} = \pm 25\text{ V}$ | | | ± 100 | nA |
| $V_{GS(TH)}$ | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{DS(on)}$ | Static drain-source on resistance | $V_{GS} = 10\text{ V}$, $I_D = 11.5\text{ A}$ | | 72 | 89 | m Ω |

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-------------------|---------------------------------------|--|------|------|------|----------|
| C_{ISS} | Input capacitance | $V_{GS} = 0\text{ V}$, $V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$ | | 1430 | | pF |
| C_{OSS} | Output capacitance | | | 78 | | pF |
| C_{RSS} | Reverse transfer capacitance | | | 10 | | pF |
| $C_{o(tr)}^{(1)}$ | Equivalent capacitance time related | $V_{GS} = 0\text{ V}$, $V_{DS} = 0\text{ to }240\text{ V}$ | | 167 | | pF |
| $C_{o(er)}^{(2)}$ | Equivalent capacitance energy related | | | 83 | | pF |
| R_G | Intrinsic gate resistance | $f = 1\text{ MHz}$ open drain | | 1.1 | | Ω |
| Q_g | Total gate charge | $V_{DS} = 240\text{ V}$, $I_D = 11.5\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$ (see Figure 16. Test circuit for gate charge behavior) | | 30.8 | | nC |
| Q_{gs} | Gate-source charge | | | 7.8 | | nC |
| Q_{gd} | Gate-drain charge | | | 14.8 | | nC |

1. Time related is defined as a constant equivalent capacitance giving the same charging time as C_{OSS} when V_{DS} increases from 0 to 80% V_{DSS} .
2. Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{OSS} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Inductive load switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit | |
|--------------------|--------------------|--|------|------|------|------|----|
| $t_d\text{ (V)}$ | Voltage delay time | $V_{DD} = 240\text{ V}$, $I_D = 23\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$ (see Figure 17. Test circuit for inductive load switching and diode recovery times and Figure 20. Switching time waveform) | | 36 | | ns | |
| $t_r\text{ (V)}$ | Voltage rise time | | | 11 | | ns | |
| $t_f\text{ (I)}$ | Current fall time | | | | 36 | | ns |
| $t_c\text{ (off)}$ | Crossing time | | | | 38 | | ns |

Table 7. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| I_{SD} | Source-drain current | | | | 23 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | | | 69 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $V_{GS} = 0\text{ V}$, $I_{SD} = 23\text{ A}$ | | | 1.5 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 23\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ | | 201 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 100\text{ V}$ (see Figure 17. Test circuit for inductive load switching and diode recovery times) | | 2.06 | | μC |
| I_{RRM} | Reverse recovery current | $V_{DD} = 100\text{ V}$ (see Figure 17. Test circuit for inductive load switching and diode recovery times) | | 20.5 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 23\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ | | 256 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 100\text{ V}$, $T_j = 150^\circ\text{C}$ | | 3.1 | | μC |
| I_{RRM} | Reverse recovery current | (see Figure 17. Test circuit for inductive load switching and diode recovery times) | | 24 | | A |

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics curves

Figure 3. Safe operating area

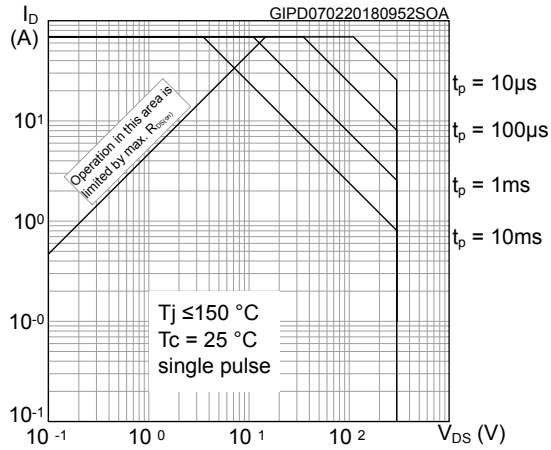


Figure 4. Thermal impedance

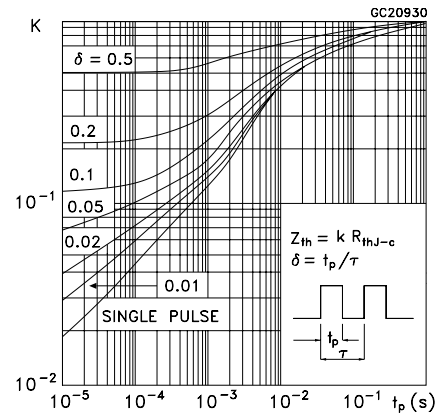


Figure 5. Output characteristics

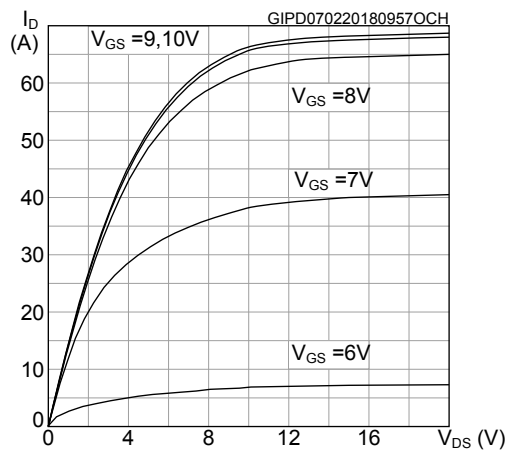


Figure 6. Transfer characteristics

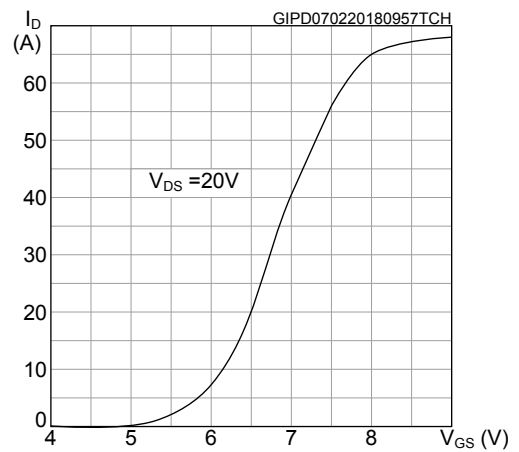


Figure 7. Normalized $V_{(BR)DSS}$ vs temperature

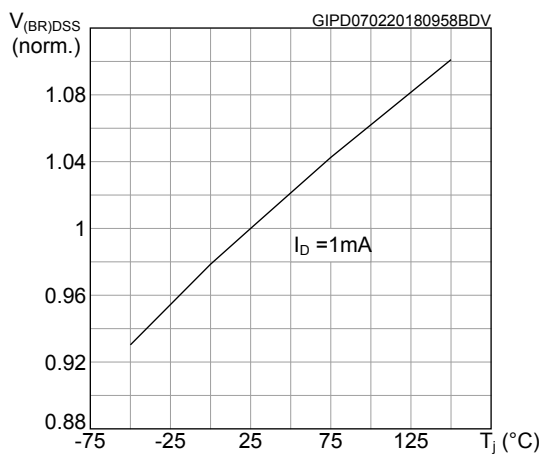


Figure 8. Static drain-source on-resistance

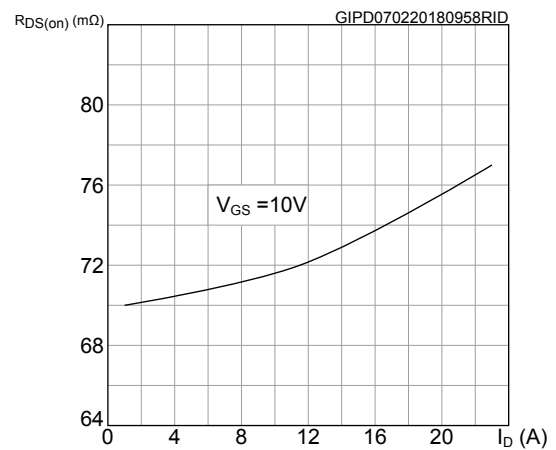


Figure 9. Gate charge vs gate-source voltage

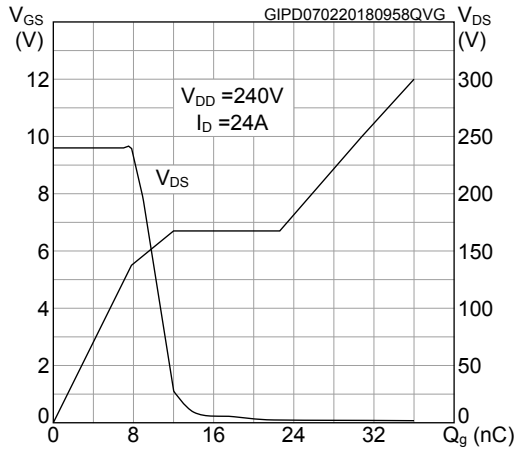


Figure 10. Capacitance variations

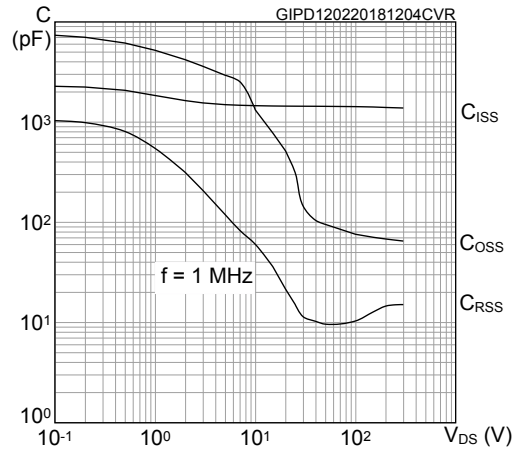


Figure 11. Normalized gate threshold voltage vs temperature

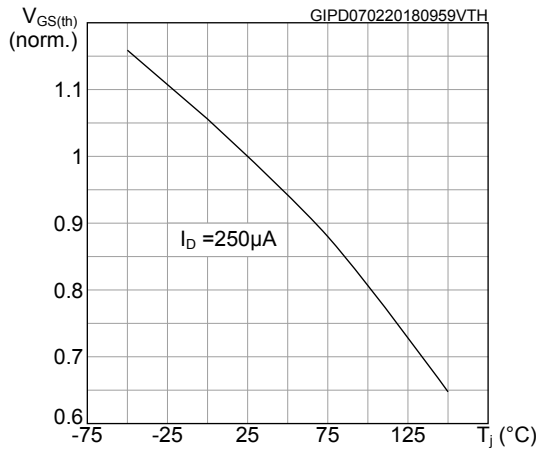


Figure 12. Normalized on-resistance vs temperature

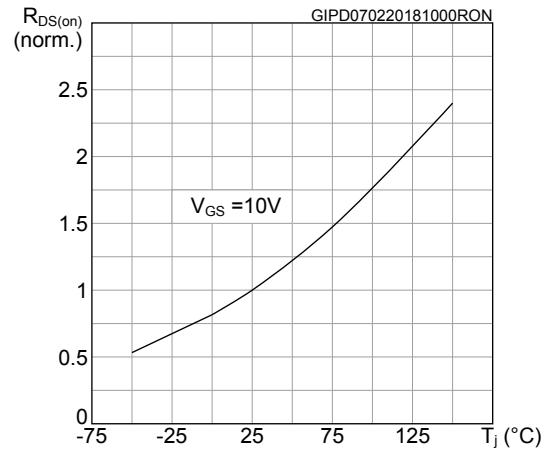


Figure 13. Output capacitance stored energy

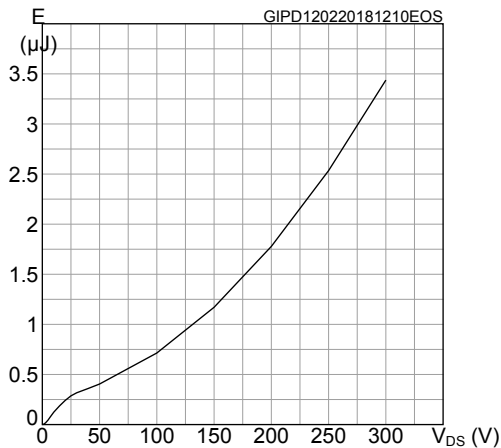
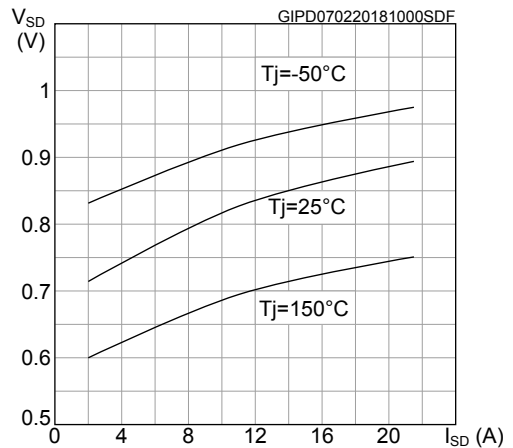
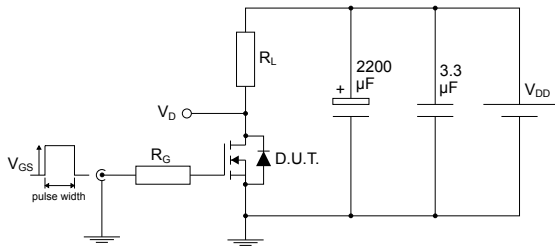


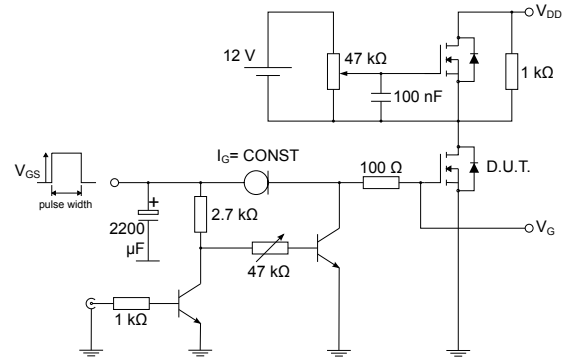
Figure 14. Source-drain diode forward characteristics



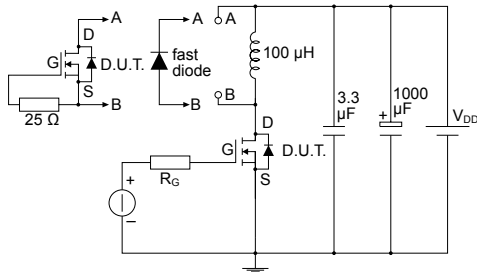
3 Test circuits

Figure 15. Test circuit for resistive load switching times


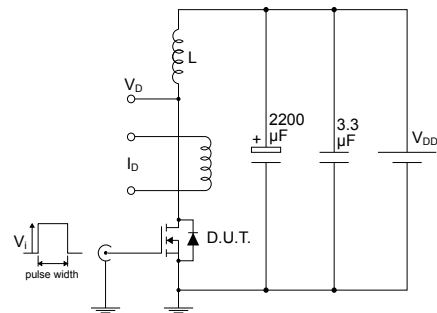
AM01468v1

Figure 16. Test circuit for gate charge behavior


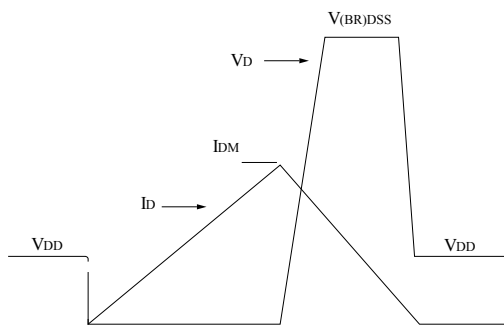
AM01469v1

Figure 17. Test circuit for inductive load switching and diode recovery times


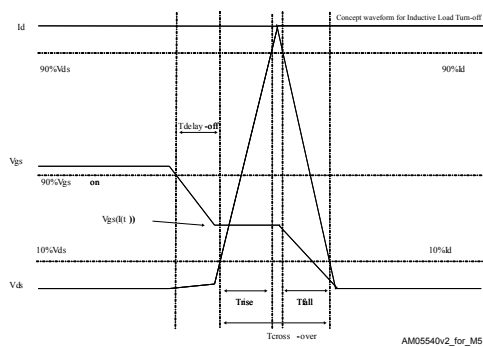
AM01470v1

Figure 18. Unclamped inductive load test circuit


AM01471v1

Figure 19. Unclamped inductive waveform


AM01472v1

Figure 20. Switching time waveform


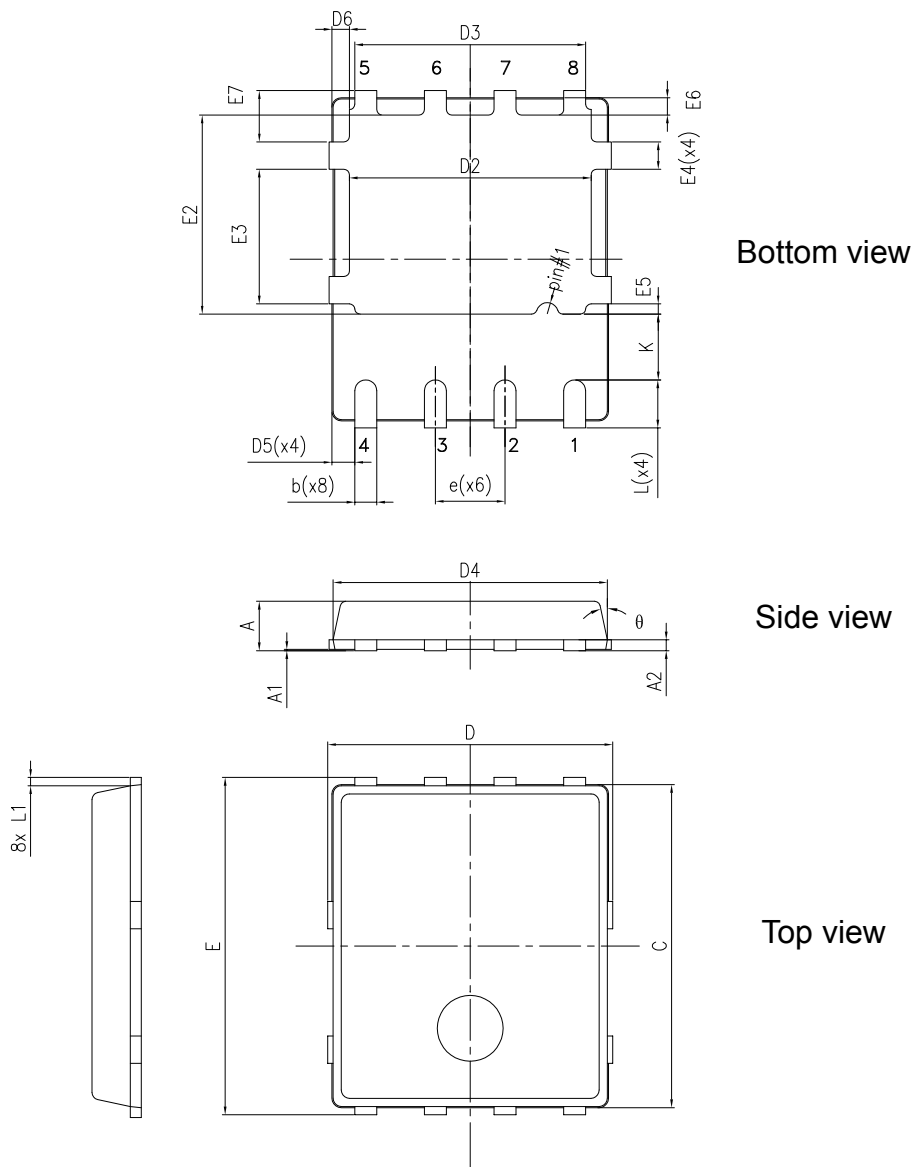
AM05540v2_for_M8

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 PowerFLAT™ 5x6 type C package information

Figure 21. PowerFLAT™ 5x6 type C package outline

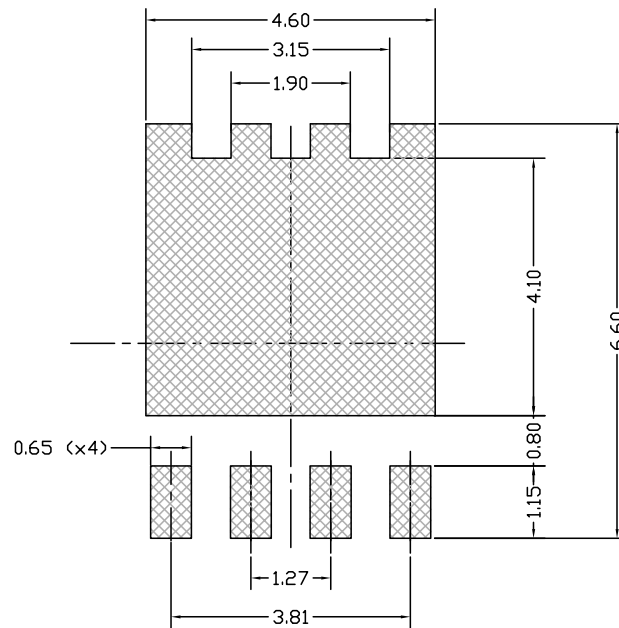


8231817_typeC_A0ER_Rev15

Table 8. PowerFLAT™ 5x6 type C package mechanical data

| Dim. | mm | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 0.80 | | 1.00 |
| A1 | 0.02 | | 0.05 |
| A2 | | 0.25 | |
| b | 0.30 | | 0.50 |
| C | 5.80 | 6.00 | 6.20 |
| D | 5.00 | 5.20 | 5.40 |
| D2 | 4.15 | | 4.45 |
| D3 | 4.05 | 4.20 | 4.35 |
| D4 | 4.80 | 5.00 | 5.20 |
| D5 | 0.25 | 0.40 | 0.55 |
| D6 | 0.15 | 0.30 | 0.45 |
| e | | 1.27 | |
| E | 5.95 | 6.15 | 6.35 |
| E2 | 3.50 | | 3.70 |
| E3 | 2.35 | | 2.55 |
| E4 | 0.40 | | 0.60 |
| E5 | 0.08 | | 0.28 |
| E6 | 0.20 | 0.325 | 0.45 |
| E7 | 0.75 | 0.90 | 1.05 |
| K | 1.05 | | 1.35 |
| L | 0.725 | | 1.025 |
| L1 | 0.05 | 0.15 | 0.25 |
| θ | 0° | | 12° |

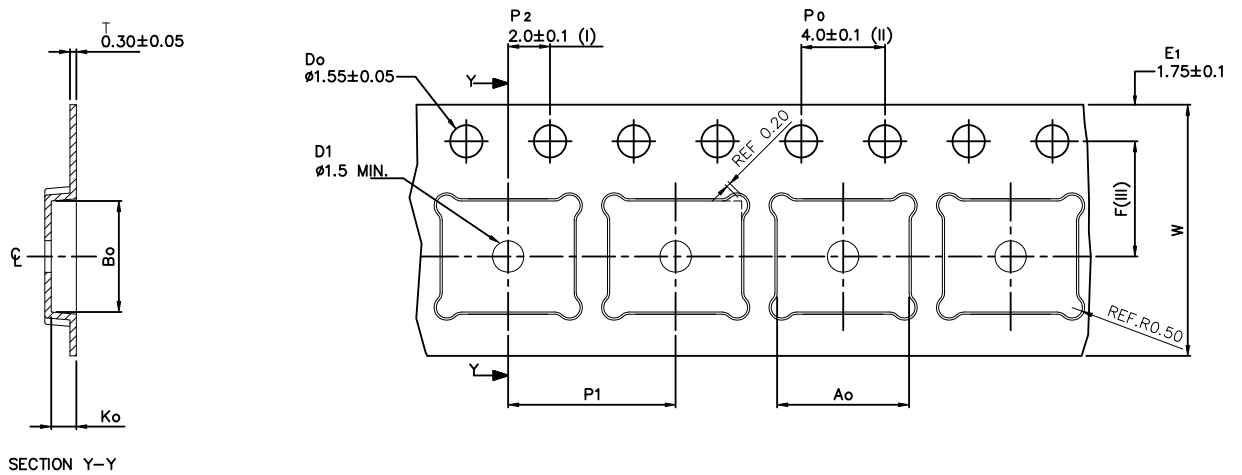
Figure 22. PowerFLAT™ 5x6 recommended footprint (dimensions are in mm)



8231817_FOOTPRINT_simp_Rev_15

4.2 PowerFLAT™ 5x6 packing information

Figure 23. PowerFLAT™ 5x6 tape (dimensions are in mm)



| | | | |
|-------|-------|-----|-----|
| A_0 | 6.30 | +/- | 0.1 |
| B_0 | 5.30 | +/- | 0.1 |
| K_0 | 1.20 | +/- | 0.1 |
| F | 5.50 | +/- | 0.1 |
| P_1 | 8.00 | +/- | 0.1 |
| W | 12.00 | +/- | 0.3 |

(I) Measured from centreline of sprocket hole to centreline of pocket.

(II) Cumulative tolerance of 10 sprocket holes is ± 0.20 .

(III) Measured from centreline of sprocket hole to centreline of pocket

Base and bulk quantity 3000 pcs
All dimensions are in millimeters

8234350_Tape_rev_C

Figure 24. PowerFLAT™ 5x6 package orientation in carrier tape

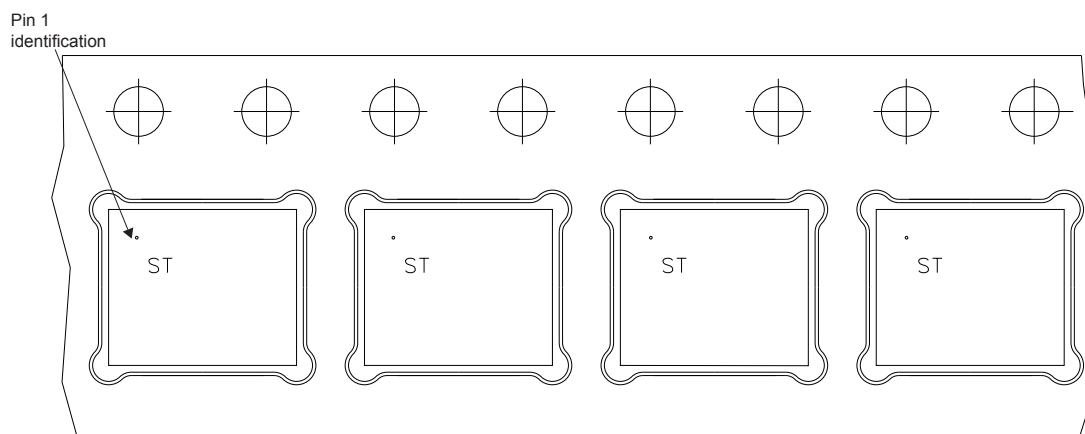
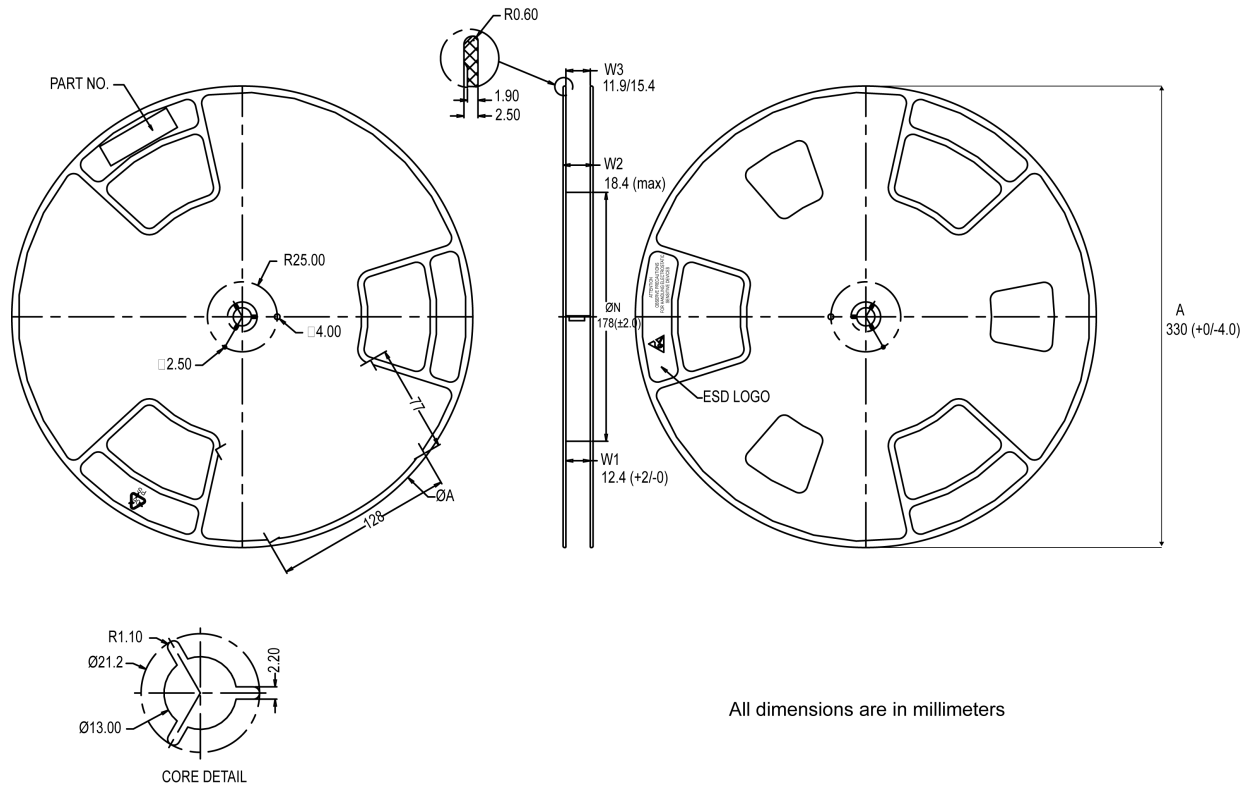


Figure 25. PowerFLAT™ 5x6 reel



All dimensions are in millimeters

8234350_Reel_rev_C

Revision history

Table 9. Document revision history

| Date | Version | Changes |
|-------------|---------|------------------|
| 07-Feb-2018 | 1 | Initial release. |

Contents

| | | |
|------------|---|-----------|
| 1 | Electrical ratings | 2 |
| 2 | Electrical characteristics | 3 |
| 2.1 | Electrical characteristics curves | 5 |
| 3 | Test circuits | 7 |
| 4 | Package information | 8 |
| 4.1 | PowerFLAT™ 5x6 type C package information | 8 |
| 4.2 | PowerFLAT™ 5x6 packing information | 11 |
| | Revision history | 13 |

IMPORTANT NOTICE – PLEASE READ CAREFULLY

STMicroelectronics NV and its subsidiaries (“ST”) reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST’s terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers’ products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2018 STMicroelectronics – All rights reserved